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(71) Applicant: **SHARP CORP**
(72) Inventor: **TAKAHASHI EIICHI**

(54) METHOD FOR INSPECTION OF LIQUID CRYSTAL DISPLAY DEVICE

(57) Abstract:

PROBLEM TO BE SOLVED: To provide a method for the inspection of a liquid crystal display device with high inspection accuracy by which a reflection type liquid crystal display device can be inspected in a bright and uniform display state.

SOLUTION: A light source 1 consisting of a point light source such as a xenon lamp or halogen lamp is disposed on an extended line of the diagonal line of a reflection type liquid crystal display device 2 equipped with a reflection layer such as a reflector and a reflection electrode having a reflecting function so as to irradiate the reflection type liquid crystal display device 2 with the light 3 from the light source 1. By this method, fluctuation in the reflection luminance can be decreased and generation of irregular reflection in stripes can be prevented. The light source 1 is disposed in such a manner that illuminance in the region 4 of the reflection liquid crystal display device 2 farthest from the light source 1 is highest, and that the illuminance decreases in steps in region 5, region 6 and region 7 nearer to the light source 1. Thus, the reflection characteristics of the reflection type liquid crystal display device are compensated to produce a homogeneous state of luminance of the display device 2, and thereby, the inspection accuracy for the display quality can be improved.